Agilent 4N25
Phototransistor Optocoupler
General Purpose Type
Data Sheet

Description
The 4N25 is an optocoupler for general purpose applications. It contains a light emitting diode optically coupled to a photo-transistor. It is packaged in a 6-pin DIP package and available in wide-lead spacing option and lead bend SMD option. Response time, t_r, is typically 3 µs and minimum CTR is 20% at input current of 10 mA.

Ordering Information
Specify part number followed by Option Number (if desired).

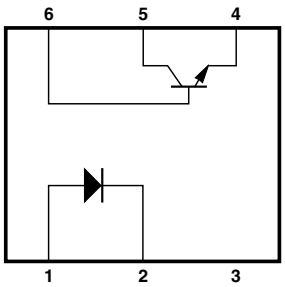
4N25-XXXE
- E = Lead Free
- XXX = Option Number

000 = No Options
060 = IEC/EN/DIN EN 60747-5-2 Option
W00 = 0.4" Lead Spacing Option
300 = Lead Bend SMD Option
500 = Tape and Reel Packaging Option

Features
- **Response time (t_r: typ., 3 µs at V_{CE} = 10 V, I_C = 2 mA, R_L = 100 Ω)**
- **Current Transfer Ratio (CTR: min. 20% at I_F = 10 mA, V_{CE} = 10 V)**
- **Input-output isolation voltage (V_{iso} = 2500 Vrms)**
- **Dual-in-line package**
- **UL approved**
- **CSA approved**
- **IEC/EN/DIN EN 60747-5-2 approved**
- **Options available:**
  - **Leads with 0.4" (10.16 mm) spacing (W00)**
  - **Leads bends for surface mounting (300)**
  - **Tape and reel for SMD (500)**
  - **IEC/EN/DIN EN 60747-5-2 approvals (060)**

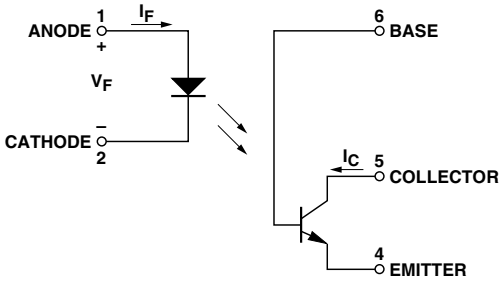
Functional Diagram

PIN NO. AND INTERNAL CONNECTION DIAGRAM



1. ANODE
2. CATHODE
3. NC
4. EMITTER
5. COLLECTOR
6. BASE

Schematic

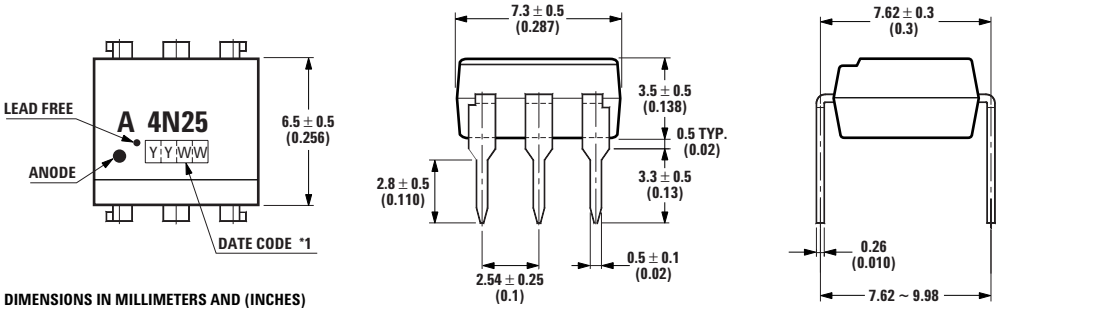


Applications
- **I/O interfaces for computers**
- **System appliances, measuring instruments**
- **Signal transmission between circuits of different potentials and impedances**

CAUTION: *It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation which may be induced by ESD.*

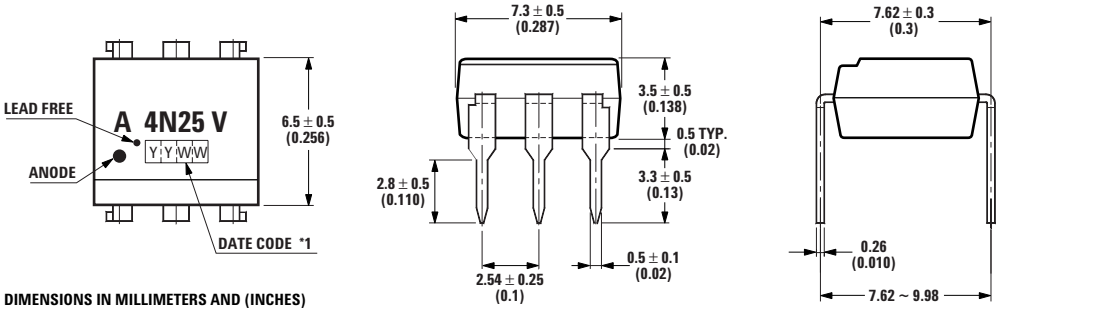
Package Outline Drawings

4N25-000E



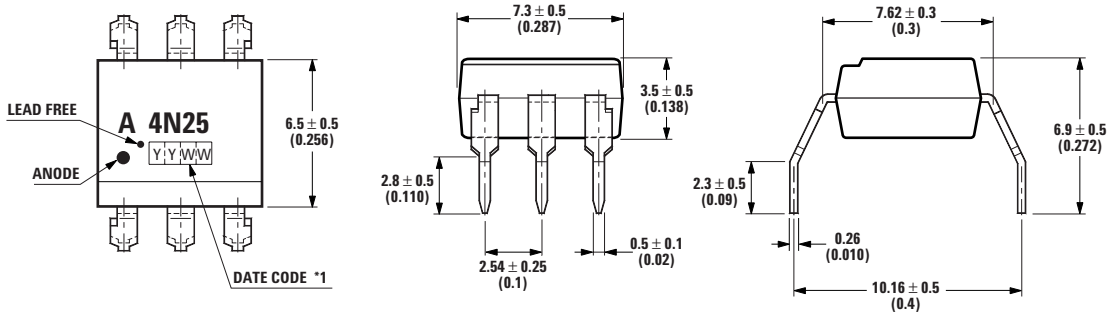
DIMENSIONS IN MILLIMETERS AND (INCHES)

4N25-060E



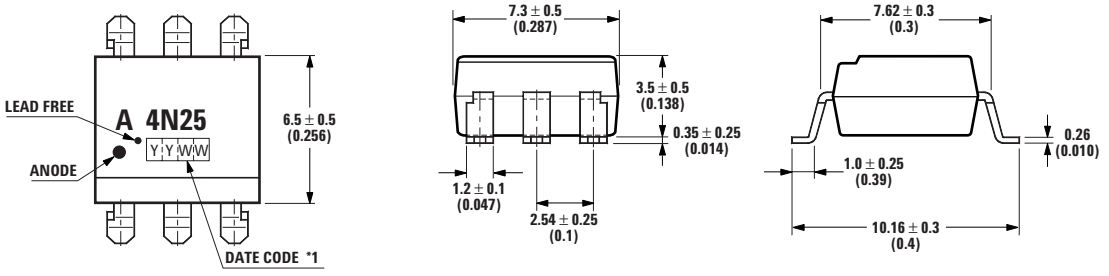
DIMENSIONS IN MILLIMETERS AND (INCHES)

4N25-W00E



DIMENSIONS IN MILLIMETERS AND (INCHES)

4N25-300E

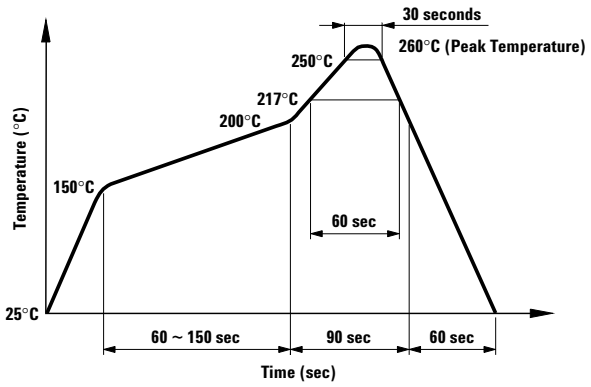


DIMENSIONS IN MILLIMETERS AND (INCHES)

Solder Reflow Temperature Profile

1) One-time soldering reflow is recommended within the condition of temperature and time profile shown at right.

2) When using another soldering method such as infrared ray lamp, the temperature may rise partially in the mold of the device. Keep the temperature on the package of the device within the condition of (1) above.



Absolute Maximum Ratings

Storage Temperature, T_S	–55˚C to +150˚C
Operating Temperature, T_A	–55˚C to +100˚C
Lead Solder Temperature, max. (1.6 mm below seating plane)	260˚C for 10 s
Average Forward Current, I_F	80 mA
Reverse Input Voltage, V_R	6 V
Input Power Dissipation, P_I	150 mW
Collector Current, I_C	100 mA
Collector-Emitter Voltage, V_{CEO}	30 V
Emitter-Collector Voltage, V_{ECO}	7 V
Collector-Base Voltage, V_{CBO}	70 V
Collector Power Dissipation	150 mW
Total Power Dissipation	250 mW
Isolation Voltage, V_{iso} (AC for 1 minute, R.H. = 40 ~ 60%)	2500 Vrms

Electrical Specifications (T_A = 25°C)

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Forward Voltage	V_F	–	1.2	1.5	V	I_F = 10 mA
Reverse Current	I_R	–	–	10	μA	V_R = 4 V
Terminal Capacitance	C_t	–	50	–	pF	V = 0, f = 1 KHz
Collector Dark Current	I_{CEO}	–	–	50	nA	V_{CE} = 10 V, I_F = 0
Collector-Emitter Breakdown Voltage	BV_{CEO}	30	–	–	V	I_C = 0.1 mA, I_F = 0
Emitter-Collector Breakdown Voltage	BV_{ECO}	7	–	–	V	I_E = 10 μA, I_F = 0
Collector-Base Breakdown Voltage	BV_{CBO}	70	–	–	V	I_C = 0.1 mA, I_F = 0
Collector Current	I_C	2	–	–	mA	I_F = 10 mA
*Current Transfer Ratio	CTR	20	–	–	%	V_{CE} = 10 V
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$	–	0.1	0.5	V	I_F = 50 mA, I_C = 2 mA
Response Time (Rise)	t_r	–	3	–	μs	V_{CE} = 10 V, I_C = 2 mA
Response Time (Fall)	t_f	–	3	–	μs	R_L = 100 Ω
Isolation Resistance	R_{iso}	5×10^{10}	1×10^{11}	–	Ω	DC 500 V 40 ~ 60% R.H.
Floating Capacitance	C_f	–	1	–	pF	V = 0, f = 1 MHz

* CTR = $\frac{I_C}{I_F}$ x 100%

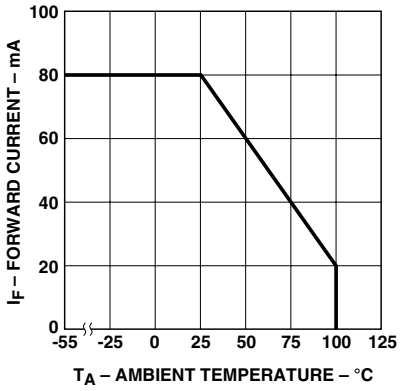


Figure 1. Forward current vs. temperature.

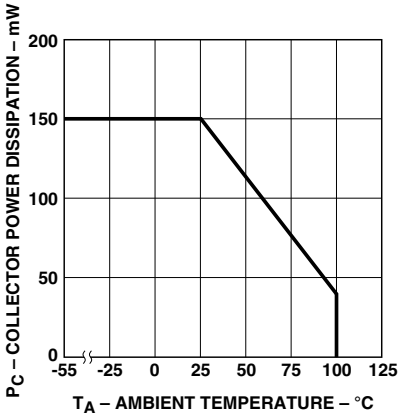


Figure 2. Collector power dissipation vs. temperature.

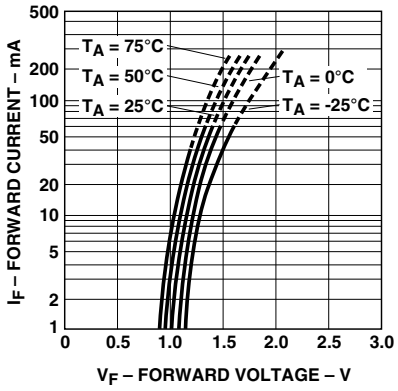


Figure 3. Forward current vs. forward voltage.

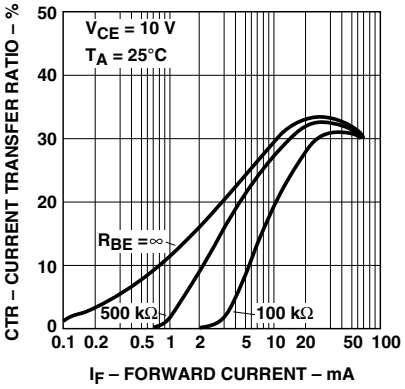


Figure 4. Current transfer ratio vs. forward current.

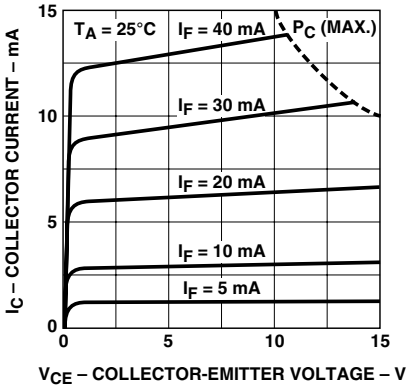


Figure 5. Collector current vs. collector-emitter voltage.

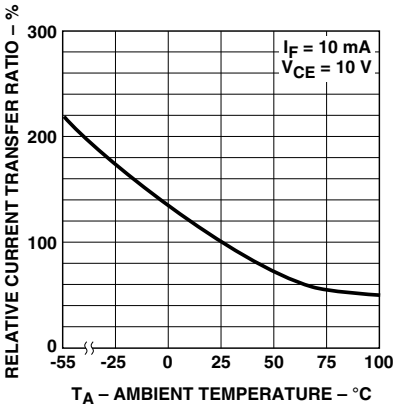


Figure 6. Relative current transfer ratio vs. temperature.

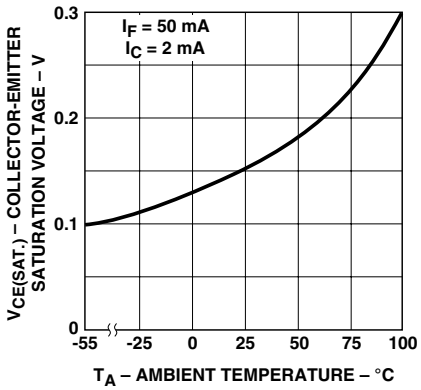


Figure 7. Collector-emitter saturation voltage vs. temperature.

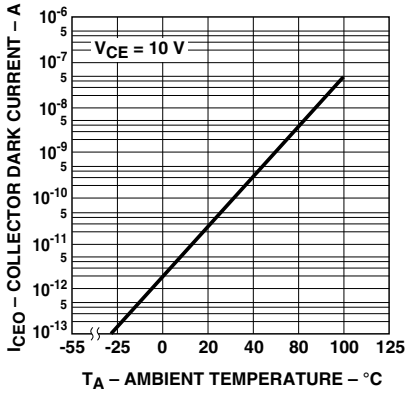


Figure 8. Collector dark current vs. temperature.

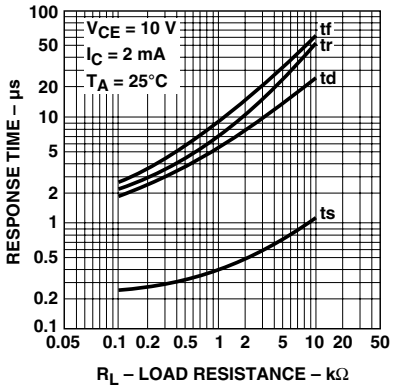


Figure 9. Response time vs. load resistance.

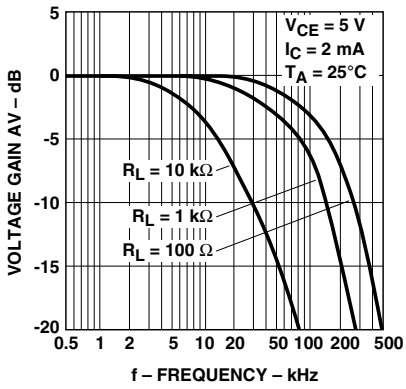


Figure 10. Frequency response.

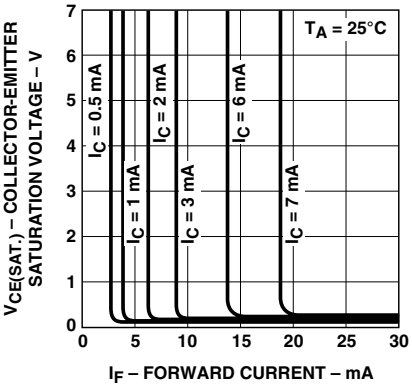
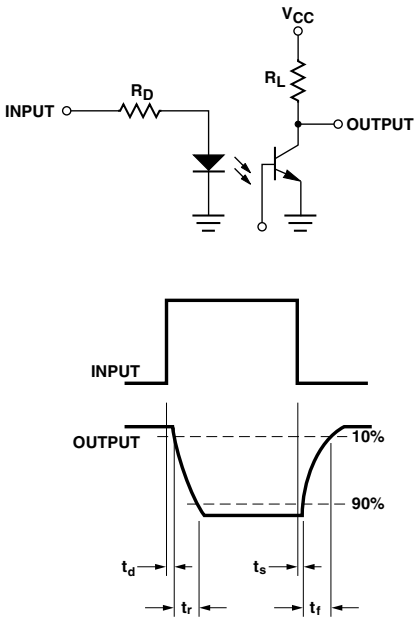
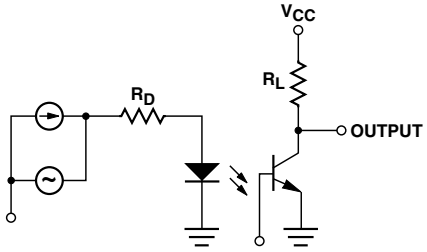


Figure 11. Collector-emitter saturation voltage vs. forward current.

Test Circuit for Response Time



Test Circuit for Frequency Response



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